

Amendments to the Claims

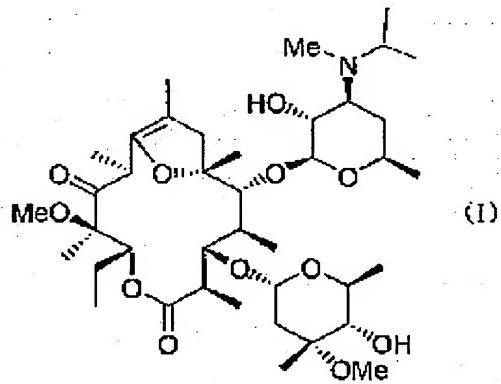
This listing of claims will replace all prior versions, and listings, of claims in the application:

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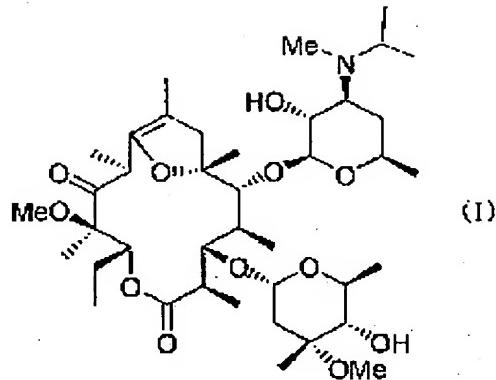
1. (Original) A hemifumarate crystal of a compound of formula (I):



characterized by 2-theta angle positions in the powder X-ray diffraction pattern of 6.6° and 8.5°.

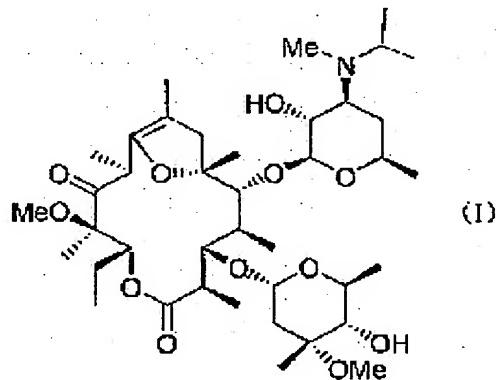
Claim 2. (Cancelled)

3. (Currently Amended) A hemifumarate x-hydrate of a compound of formula (I):



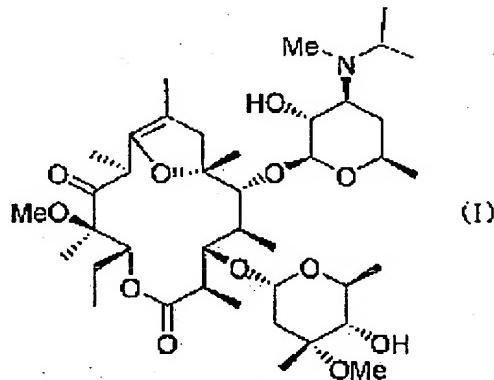
characterized by 2-theta angle positions in the powder X-ray diffraction pattern of 7.1° and 14.2°.

4. (Currently Amended) A process for preparing a hemifumarate X-hydrate of a compound of formula (I) :



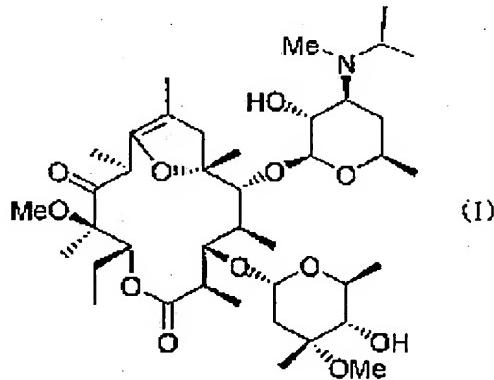
characterized by 2-theta angle positions in the powder X-ray diffraction pattern of 7.1°, said process comprising the step of treating conditioning a hemifumarate anhydrate of the compound of formula (I) characterized by 2-theta angle positions in the powder X-ray diffraction pattern of 7.1°, 13.5° and 14.2°, to obtain said hemifumarate X-hydrate.

5. (Currently Amended) A process for preparing a hemifumarate anhydrate of a compound of formula (I):



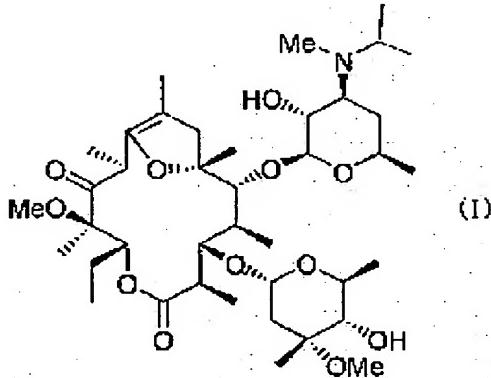
characterized by 2-theta angle positions in the powder X-ray diffraction pattern of  $7.1^\circ$ ,  $13.5^\circ$  and  $14.2^\circ$ , said process comprising the step of treating drying under reduced pressure a hemifumarate crystal form of the compound of formula (I) characterized by 2-theta angle positions in the powder X-ray diffraction pattern of  $6.6^\circ$  and  $8.5^\circ$ , to obtain said hydrate.

6. (Currently Amended) A process for preparing a hemifumarate ~~X~~-hydrate of a compound of formula (I):



characterized by 2-theta angle positions in the powder X-ray diffraction pattern of  $7.1^\circ$  and  $14.2^\circ$ , said process comprising the step of treating drying under reduced pressure a hemifumarate crystal of the compound of formula (I)  $6.6^\circ$  and  $8.5^\circ$ , to obtain said hydrate.

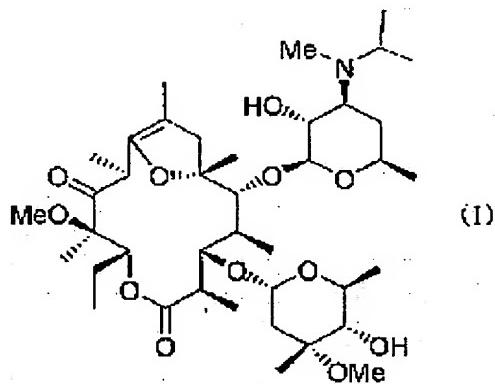
7. (Currently Amended) A process for preparing a hemifumarate X-hydrate of a compound of formula (I):



characterized by 2-theta angle positions in the powder X-ray diffraction pattern of  $7.1^\circ$  and  $14.2^\circ$ , said process comprising the step of treating conditioning a hemifumarate anhydrate of the compound of formula (I) characterized by 2-theta angle positions in the powder X-ray diffraction pattern of  $7.1^\circ$ ,  $13.5^\circ$  and  $14.2^\circ$ , wherein said hemifumarate anhydrate is obtained by treating drying under reduced pressure a hemifumarate crystal of the compound of formula (I) characterized by 2-theta angle positions in the powder X-ray

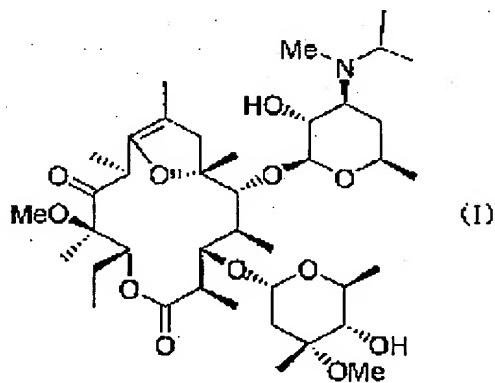
diffraction pattern of  $6.6^\circ$  and  $8.5^\circ$ .

8. (Original) A hemifumarate crystal of a compound of formula (I) :



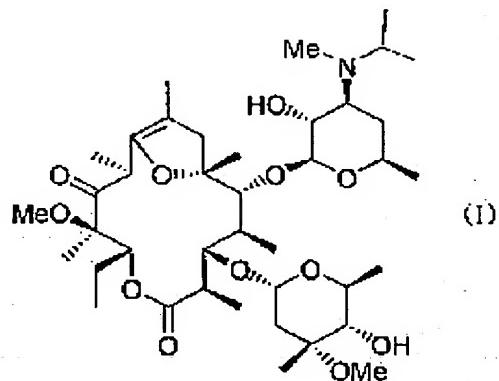
characterized by 2-theta angle positions in the powder X-ray diffraction pattern of  $5.4^\circ$ ,  $10.4^\circ$ ,  $10.7^\circ$  and  $12.1^\circ$ .

9. (Original) A hemifumarate crystal of a compound of formula (I) :



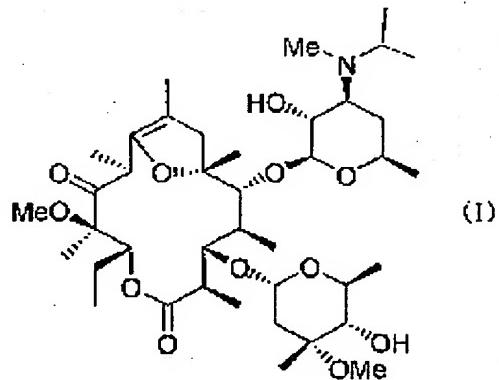
containing acetone and showing strong X-ray diffraction peaks at diffraction angles  $2\ \text{theta} = 5.4^\circ$ ,  $10.4^\circ$ ,  $10.7^\circ$  and  $12.1^\circ$  measured by X-ray diffractometry using Cu-K $\alpha$  radiation.

10. (Currently Amended) A hemifumarate crystal of a compound of formula (I):



containing methylethylketone and showing strong X-ray diffraction peaks at diffraction angles  $2\ \theta = 5.4^\circ, 10.4^\circ, 10.7^\circ$  and  $12.1^\circ$  measured by X-ray diffractometry using Cu-K $\alpha$  radiation.

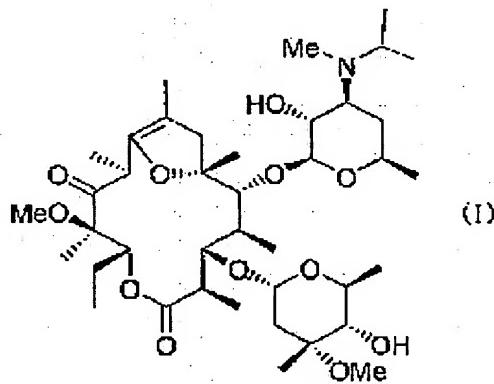
11. (Original) A hemifumarate crystal of a compound of formula (I):



containing tetrahydrofuran and showing strong X-ray diffraction peaks at diffraction angles 2 theta = 5.4°, 10.4°, 10.7° and 12.1° measured by X-ray diffractometry using Cu-Kα radiation.

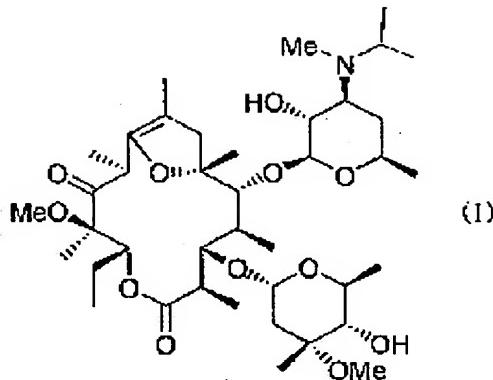
Claims 12-15. (Cancelled)

16. (Currently Amended) A process for preparing a hemifumarate anhydrate of a compound of formula (I):



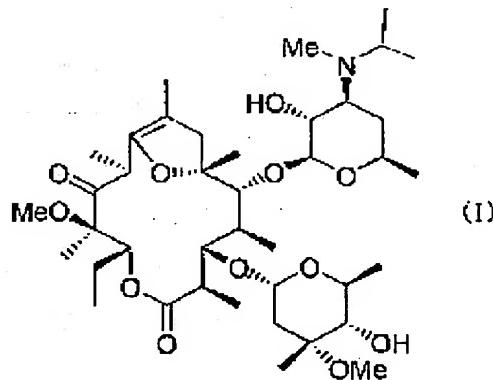
characterized by 2-theta angle positions in the powder X-ray diffraction pattern of 7.1°, 13.5° and 14.2°, said process comprising the step of obtaining said anhydrate by ~~treating~~ drying under reduced pressure a hemifumarate crystal of Claim 8, 9, 10 or 11.

17. (Currently Amended) A process for preparing a hemifumarate ~~X~~-hydrate of a compound of formula (I):



characterized by 2-theta angle positions in the powder X-ray diffraction pattern of showing strong X-ray diffraction peaks at diffraction angles  $2\theta = 7.1^\circ$  and  $14.2^\circ$ , said process comprising the step of obtaining said hydrate by ~~treating~~ drying under reduced pressure a hemifumarate crystal of Claim 8, 9, 10 or 11.

18. (Currently Amended) A process for preparing a hemifumarate  $\alpha$ -hydrate of a compound of formula (I):



characterized by 2-theta angle positions in the powder X-ray diffraction pattern of  $7.1^\circ$  and  $14.2^\circ$ , said process comprising

the step of treating conditioning a hemifumarate anhydrate of the compound of formula (I) characterized by 2-theta angle positions in the powder X-ray diffraction pattern of 7.1°, 13.5° and 14.2°, wherein said anhydrate is obtained by treating drying under reduced pressure a hemifumarate crystal of Claim 8, 9, 10 or 11.